



Title of Change:	Adding Nitride Passivation layer on P-Zener devices.			
Proposed first ship date:	23 December 2016			
Contact information:	Contact your local ON Semiconductor Sales Office or <Syahrul.SamsuddinA.Rahim@onsemi.com>			
Samples:	Contact your local ON Semiconductor Sales Office			
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Nicky.Siu@onsemi.com >			
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change. ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <PCN.Support@onsemi.com>.			
Change Part Identification:	Affected products will be identified with date code			
Change category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____			
Change Sub-Category(s):	<input type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input checked="" type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____			
Sites Affected:	<input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input checked="" type="checkbox"/> ON Semiconductor site(s) : ON ISMF, Malaysia <input type="checkbox"/> External Foundry/Subcon site(s)			
Description and Purpose:				
As a part of ON Semiconductor's continuous improvement, this FPCN is issued to announce that Passivation change will occur with adding a Nitride Passivation Layer on P-Zener devices				
Reliability Data Summary:				
QV DEVICE NAME : SZMMBZ33VALT1G PACKAGE: SOT-23				
Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	1008 hrs	0/231
PC	J-STD-020 JESD-A113	MSL 1 @ 260 °C. Performed prior to TC and HAST test.	Post PC	0/462
TC	JESD22-A104	Ta= -65°C to +150°C	1000 cyc	0/231
HAST	JESD22-A110	130°C, 85% RH, 18.8psig, bias	96 hrs	0/231
To access file attachments on pdf copy of PCN, please be guided by the steps below: 1. Download pdf copy of the PCN to your computer 2. Open the downloaded pdf copy of the PCN 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field 4. Then click on the attached file/s				
Electrical Characteristic Summary:				
Electrical characteristics are not impacted				
List of Affected Standard Parts:				
Part Number		Qualification Vehicle		
SZESD9X12ST5G		SZMMBZ33VALT1G		
SZNUP3112UPMUTAG				
SZSMF12CT1G				